

<b>Notice of References Cited</b>	Application/Control No. 10/635,000	Applicant(s)/Patent Under Reexamination EOM, WOO-SIK	
	Examiner Fritz Alphonse	Art Unit 2133	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,029,208	02-2000	Kim, Young-chul	710/4
*	B	US-5,621,734	04-1997	Mann et al.	709/227
*	C	US-6,160,777	12-2000	Kim, Han Gyoan	369/47.36
*	D	US-6,181,660	01-2001	Hirayama et al.	369/59.1
*	E	US-6,519,715	02-2003	Takashi et al.	714/32
*	F	US-6,757,231	06-2004	Fujiwara, Kazunobu	369/53.35
*	G	US-6,564,352	05-2003	Furuhashi et al.	714/801
*	H	US-6,747,942	06-2004	Tanoue et al.	369/275.3
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.